

33rd RD50 Workshop (CERN)

Tuesday 27 November 2018

Device Simulation - 6/2-024 - BE Auditorium Meyrin (14:10 - 15:20)

-Conveners: Joern Schwandt

time	[id] title	presenter
14:10	[2] Charge collection test and TCAD simulation of OVERMOS, a CMOS 180nm MAPS detector	Dr VILLANI, E. Giulio VILLANI, Enrico Giulio VILLANI, Enrico Giulio VILLANI, Giulio
14:30	[4] Status on TRAMOS (Trapping MOS) and DotPix (QuantumDot Pixel) ongoing developments	Dr FOURCHES, Nicolas
14:50	[33] Discussion	SCHWANDT, Joern BOMBEN, Marco BOMBEN, Marco